

MAC8SDG, MAC8SMG, MAC8SNG





Description

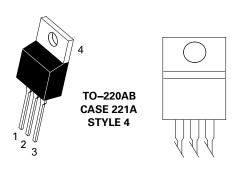
Designed primarily for full-wave ac control applications, such as motor controls, heating controls and power supplies; or wherever half-wave silicon gate-controlled, solid-state devices are needed.

Features

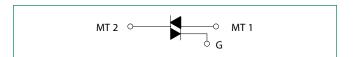
- Sensitive Gate
 Allows Triggering by
 Microcontrollers and other
 Logic Circuits
- Uniform Gate Trigger Currents in Three Quadrants; Q1, Q2, and Q3
- High Immunity to dv/dt 25 V/µs Minimum at 110°C
- High Commutating di/ dt – 8.0 A/ms Minimum at 110°C
- Maximum Values of IGT, VGT and IH Specified for Ease of Design

- On-State Current Rating of 8 Amperes RMS at 70°C
- High Surge Current Capability – 70 Amperes
- Blocking Voltage to 800 Volts
- Rugged, Economical TO-220 Package
- These Devices are Pb-Free and are RoHS Compliant

Pin Out



Functional Diagram



Additional Information







Resources

Thyristors

Maximum Ratings (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off-State Voltage (Note 1) (Gate Open, Sine Wave 50 to 60 Hz, $T_J = 25^{\circ}$ to 100°C)	V _{DRM} ,	400 600 800	V
On-State RMS Current (Full Cycle Sine Wave, 60 Hz, T _C = 100°C)	I _{T (RMS)}	8.0	А
Peak Non-Repetitive Surge Current (One Full Cycle Sine Wave, 60 Hz, T _C = 125°C)	I _{TSM}	70	А
Circuit Fusing Consideration (t = 8.3 ms)	l²t	20	A²sec
Peak Gate Power (Pulse Width ≤ 1.0 µs, T _C = 80°C)	P _{GM}	16	W
Average Gate Power (t = 8.3 ms, T_c = 80°C)	P _{G(AV)}	0.35	W
Operating Junction Temperature Range	T _J	-40 to +110	°C
Storage Temperature Range	T _{stg}	-40 to +110	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied.

Thermal Characteristics

Ratiı	Symbol	Value	Unit	
Thermal Resistance,	Junction-to-Case (AC) Junction-to-Ambient	R _{ejc} R _{eja}	2.2 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds		T _L	260	°C

Electrical Characteristics - OFF $(T_1 = 25^{\circ}\text{C unless otherwise noted}; \text{Electricals apply in both directions})$

Characteristic		Symbol	Min	Тур	Max	Unit
Peak Repetitive Blocking Current	T ₁ = 25°C	I _{DRM} ,	-	-	0.01	A
$(V_D = V_{DRM} = V_{RRM}; Gate Open)$	T _J = 125°C	I _{RRM}	-	-	2.0	mA

Electrical Characteristics - ON (T_J = 25°C unless otherwise noted; Electricals apply in both directions)

Characteristic		Symbol	Min	Тур	Max	Unit
Peak On-State Voltage (Note 4) ($I_{TM} = \pm 11 \text{ A}$)		V _{TM}	_	_	1.85	V
Gate Trigger Current	MT2(+), G(+)		_	2.0	5.0	mA
(Continuous dc)	MT2(+), G(-)	I _{GT}	_	3.0	5.0	
$(V_D = 12 \text{ V}, \text{ R}_L = 100 \Omega)$	MT2(-), G(-)		_	3.0	5.0	
Holding Current ($V_D = 12 \text{ V}$, Gate Open, Initiating Current = $\pm 150 \text{ mA}$)		I _H	-	3.0	10	mA
	MT2(+), G(+)		_	5.0	15	
Latching Current $(V_n = 24 \text{ V, } I_c = 5 \text{ mA})$	MT2(+), G(-)	I _L	_	10	20	mA
(v _D = 24 v, 1 _G = 3 111A)	MT2(-), G(-)		_	5.0	15	
	MT2(+), G(+)		0.45	0.62	1.5	
Gate Trigger Voltage $(V_D = 12 \text{ V}, R_L = 100 \Omega)$	MT2(+), G(-)	V _{GT}	0.45	0.60	1.5	V
	MT2(-), G(-)		0.45	0.65	1.5	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 2. Indicates Pulse Test: Pulse Width \leq 2.0 ms, Duty Cycle \leq 2%.

Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. V_{DRM} and V_{RRM} for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.



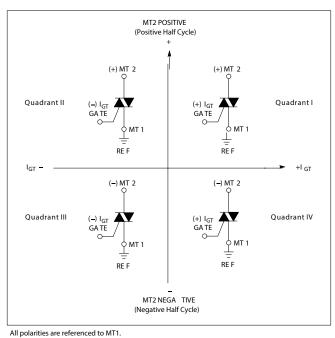
Dynamic Characteristics

Characteristic	Symbol	Min	Тур	Max	Unit
Rate of Change of Commutating Current See Figure 10. ($V_D = 400 \text{ V}$, $I_{TM} = 4.4 \text{ A}$, Commutating dv/dt = 18 V/ μ s, Gate Open, TJ = 125°C, f = 250 Hz, No Snubber) $C_L = 10 \ \mu\text{F}$ $L_L = 40 \ \text{mH}$	dV/dt	8.0	10	_	A/ms
Critical Rate of Rise of Off-State Voltage ($V_D = Rated V_{DRM'}$ Exponential Waveform, $R_{GK} = 510 \Omega$, $T_J = 110$ °C)	dV/dt	25	75	_	V/µs

Voltage Current Characteristic of SCR

Symbol	Parameter		
V _{DRM}	Peak Repetitive Forward Off State Voltage		
I _{DRM}	Peak Forward Blocking Current		
V_{RRM}	Peak Repetitive Reverse Off State Voltage		
IRRM	Peak Reverse Blocking Current		
V _{TM}	Maximum On State Voltage		
I _H	Holding Current		

Quadrant Definitions for a Triac



With in—phase signals (using standard AC lines) quadrants I and III are used

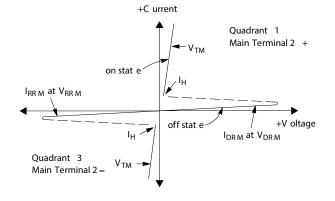




Figure 1. RMS Current Derating

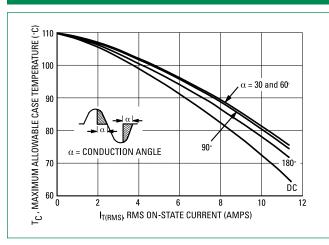


Figure 2. Maximum On-State Power Dissipation

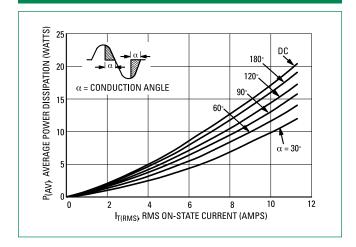


Figure 3. On-State Characteristics

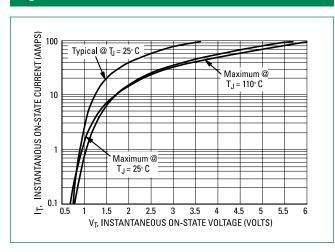


Figure 4. Transient Thermal Response

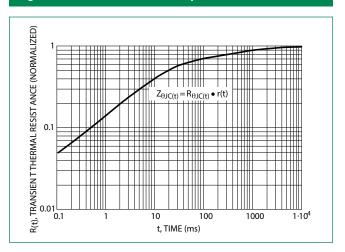


Figure 5. Typical Holding Current Vs. Junction Temperature

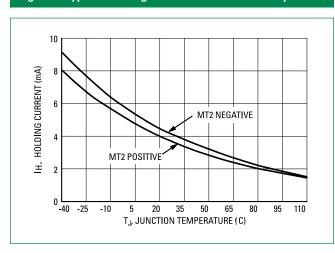


Figure 6. Typical Latching Current Vs. Junction Temperature

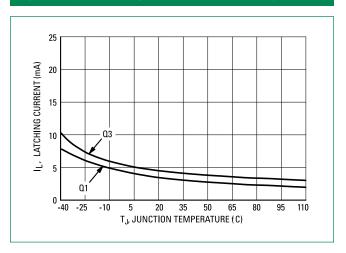




Figure 7. Typical Gate Trigger Current Vs. Junction Temperature

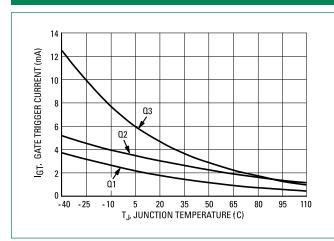


Figure 9. Typical Exponential Static dv/dt Vs. Gate–MT1 Resistance, MT2(+)

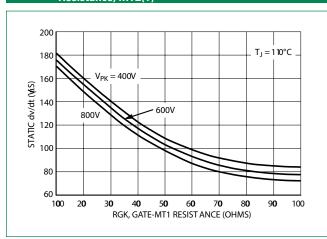


Figure 11. Typical Exponential Static dv/dt Vs. Junction Temperature, MT2(+)

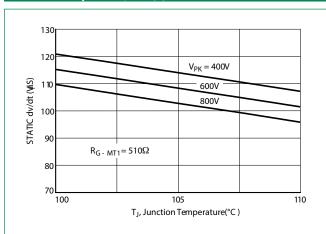


Figure 8. Typical Gate Trigger Voltage Vs. Junction Temperature

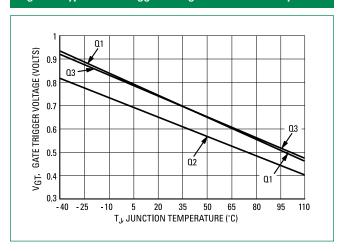


Figure 10. Typical Exponential Static dv/dt Versus Peak Voltage, MT2(+)

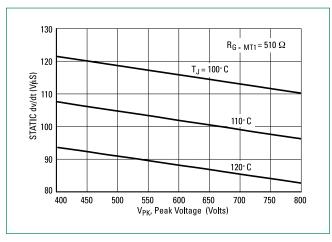


Figure 12. Typical Exponential Static dv/dt Vs. Peak Voltage, MT2(-)

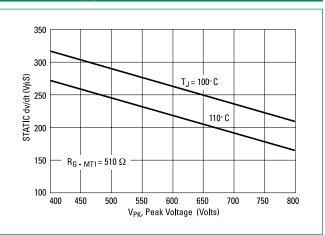




Figure 13. Typical Exponential Static dv/dt Versus Junction Temperature, MT2(-)

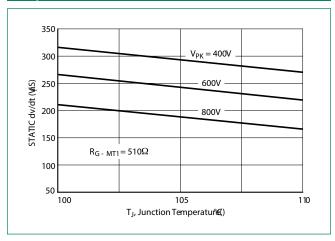


Figure 14. Typical Exponential Static dv/dt Versus Gate-MT1
Resistance MT2(-)

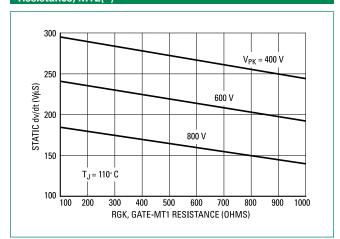


Figure 15. Critical Rate of Rise of Commutating Voltage

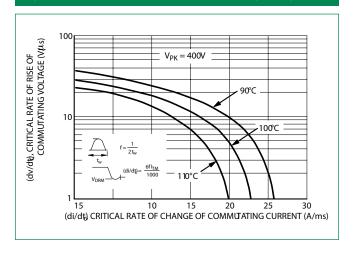
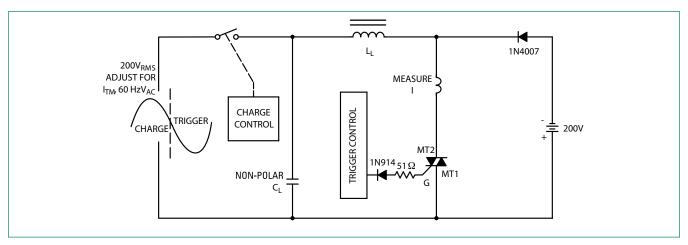


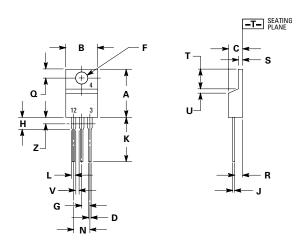
Figure 16. Simplified Test Circuit to Measure the Critical Rate of Rise of Commutating Current (di/dt)



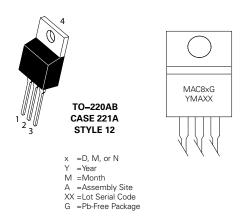
Note: Component values are for verification of rated (di/dt)_c. See AN1048 for additional information.



Dimensions



Part Marking System



	Inches Min Max		Millin	neters
Dim			Min	Max
Α	0.590	0.620	14.99	15.75
В	0.380	0.420	9.65	10.67
С	0.178	0.188	4.52	4.78
D	0.025	0.035	0.64	0.89
F	0.142	0.147	3.61	3.73
G	0.095	0.105	2.41	2.67
Н	0.110	0.130	2.79	3.30
J	0.018	0.024	0.46	0.61
K	0.540	0.575	13.72	14.61
L	0.060	0.075	1.52	1.91
N	0.195	0.205	4.95	5.21
Q	0.105	0.115	2.67	2.92
R	0.085	0.095	2.16	2.41
S	0.045	0.060	1.14	1.52
Т	0.235	0.255	5.97	6.47
U	0.000	0.050	0.00	1.27
V	0.045		1.15	
Z		0.080		2.04

Pin Assignment				
1	Main Terminal 1			
2	Main Terminal 2			
3	Gate			
4	No Connection			

Ordering Information					
Device	Package	Shipping			
MAC8SDG					
MAC8SMG	TO-220AB (Pb-Free)	500 Units / Rail			
MAC8SNG	(1.5.1.55)				

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 2. CONTROLLING DIMENSION: INCH.
- 3. DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

Mouser Electronics

Authorized Distributor

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Littelfuse:

MAC8SDG MAC8SMG MAC8SNG